

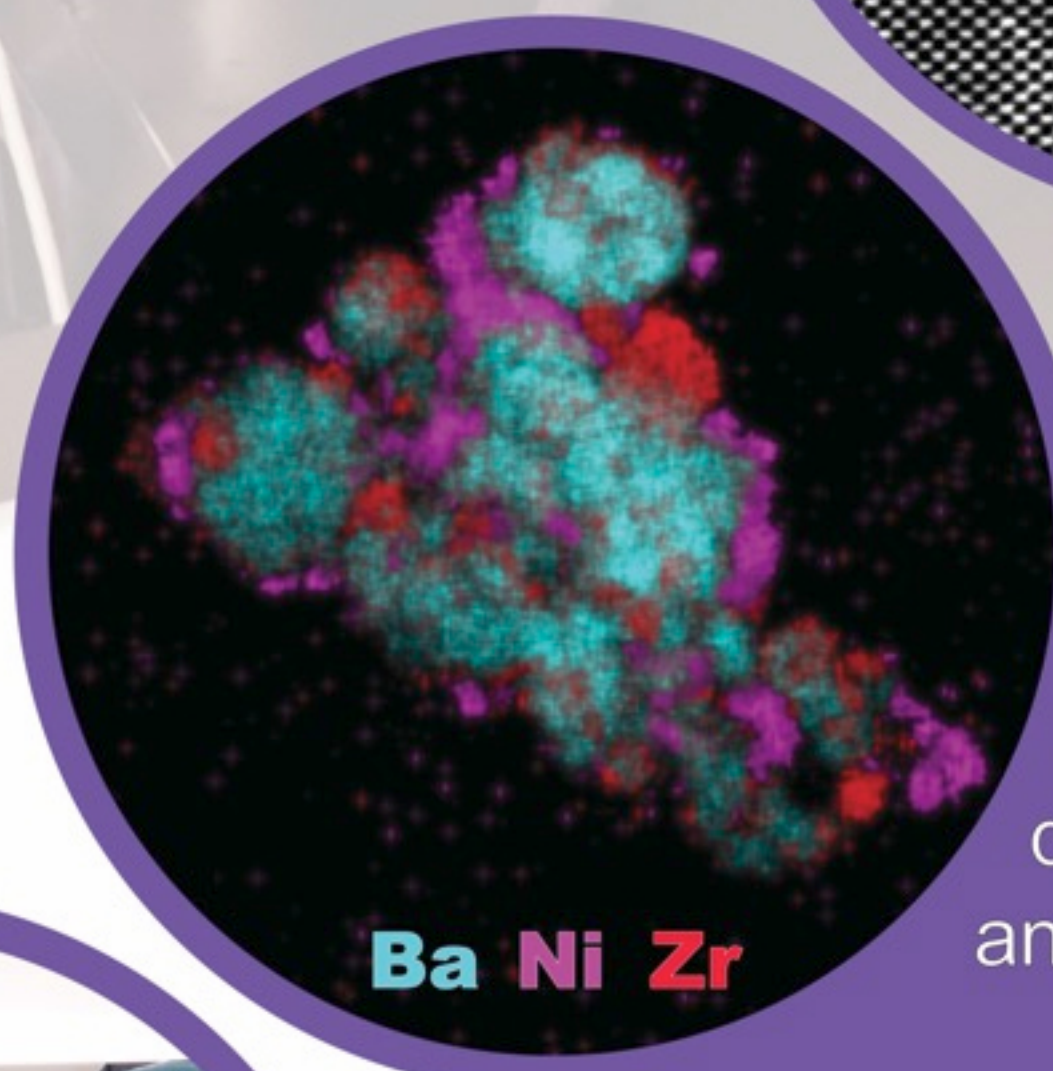
TALOS

Talos 200 S/TEM

- Atomic resolution imaging and elemental analysis
- Customized fittings are available to perform in situ dynamic experiments in real time



Atomic resolution image of silicon single crystal in 110-orientation. Resolution limit of 0.17nm almost allows the “dumbbells” to be visually separated.



Barium particles coated with nickel and zirconium. Each element detected by EDS is depicted in a unique color to show their location and relationship to the other elements.



CAMMA
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